

# Search Notes



Application/Control No.

10/550,202

Examiner

Sang Y. Paik

Applicant(s)/Patent under Reexamination

TANAKA ET AL.

Art Unit

3742

## SEARCHED

Class	Subclass	Date	Examiner
372	416- 418		
219	412- 414,		
	483-		
	495		
118	724		
	725	1/21/07	
updated		7/19/07	JP
		12/14/07	JP

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
As above		12/14/07	JP

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EST. RE. SEARCHED	1/30/07	JP